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Kind regards,

Team Nexperia

PBSS4112PAN

120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

29 November 2012

Product data sheet

Product profile 1.

1.1 General description

NPN/NPN low V_{CEsat} Breakthrough In Small Signal (BISS) transistor in a leadless medium power DFN2020-6 (SOT1118) Surface-Mounted Device (SMD) plastic package. NPN/PNP complement: PBSS4112PANP. PNP/PNP complement: PBSS5112PAP.

1.2 Features and benefits

- Very low collector-emitter saturation voltage V_{CEsat}
- High collector current capability I_C and I_{CM}
- High collector current gain her at high IC
- Reduced Printed-Circuit Board (PCB) requirements
- High energy efficiency due to less heat generation
- AEC-Q101 qualified

1.3 Applications

- Load switch
- Battery-driven devices
- Power management
- Charging circuits
- Power switches (e.g. motors, fans)

1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit	
Per transisto	Per transistor							
V _{CEO}	collector-emitter voltage	open base		-	-	120	V	
I _C	collector current			-	-	1	Α	
I _{CM}	peak collector current	single pulse; t _p ≤ 1 ms		-	-	1.5	Α	
Per transisto	r							
R _{CEsat}	collector-emitter saturation resistance	I_C = 500 mA; I_B = 50 mA; pulsed; $t_p \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C		-	-	240	mΩ	





NXP Semiconductors

120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol	
1	E1	emitter TR1	6 5 4	C1 B2 E2	
2	B1	base TR1			
3	C2	collector TR2	7 8 E1 B1 C2 Transparent top view DFN2020-6 (SOT1118)	(TR1) TR2)	
4	E2	emitter TR2			
5	B2	base TR2			
6	C1	collector TR1		sym140	
7	C1	collector TR1	DI 142020-3 (0011110)		
8	C2	collector TR2			

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PBSS4112PAN	DFN2020-6	plastic thermal enhanced ultra thin small outline package; no leads; 6 terminals; body 2 x 2 x 0.65 mm	SOT1118

4. Marking

Table 4. Marking codes

Type number	Marking code
PBSS4112PAN	2R

5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit		
Per transist	Per transistor							
V_{CBO}	collector-base voltage	open emitter		-	120	V		
V_{CEO}	collector-emitter voltage	open base		-	120	V		
V _{EBO}	emitter-base voltage	open collector		-	7	V		
I _C	collector current			-	1	Α		
I _{CM}	peak collector current	single pulse; t _p ≤ 1 ms		-	1.5	Α		
I _B	base current			-	0.3	Α		
PBSS4112PAN	BSS4112PAN All information provided in this document is subject to legal disclaimers. © NXP B.V. 2012. All rights reserved							

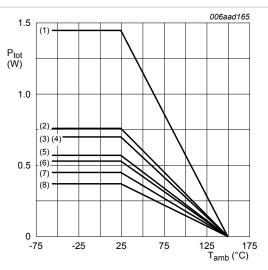
120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

Symbol	Parameter	Conditions		Min	Max	Unit
I _{BM}	peak base current	single pulse; t _p ≤ 1 ms		-	1	Α
P _{tot}	total power dissipation	T _{amb} ≤ 25 °C	[1]	-	370	mW
			[2]	-	570	mW
			[3]	-	530	mW
			[4]	-	700	mW
			<u>[5]</u>	-	450	mW
			<u>[6]</u>	-	760	mW
			[7]	-	700	mW
			[8]	-	1450	mW
Per device						
P _{tot}	total power dissipation	T _{amb} ≤ 25 °C	[1]	-	510	mW
			[2]	-	780	mW
			[3]	-	730	mW
			[4]	-	960	mW
			<u>[5]</u>	-	620	mW
			<u>[6]</u>	-	1040	mW
			[7]	-	960	mW
			[8]	-	2000	mW
Tj	junction temperature			-	150	°C
T _{amb}	ambient temperature			-55	150	°C
T _{stg}	storage temperature			-65	150	°C

- [1] Device mounted on an FR4 PCB, single-sided 35 µm copper strip line, tin-plated and standard footprint.
- 2] Device mounted on an FR4 PCB, single-sided 35 μm copper strip line, tin-plated, mounting pad for collector 1 cm².
- [3] Device mounted on 4-layer PCB 35 µm copper strip line, tin-plated and standard footprint.
- [4] Device mounted on 4-layer PCB 35 µm copper strip line, tin-plated, mounting pad for collector 1 cm².
- [5] Device mounted on an FR4 PCB, single-sided 70 µm copper strip line, tin-plated and standard footprint.
- [6] Device mounted on an FR4 PCB, single-sided 70 µm copper strip line, tin-plated, mounting pad for collector 1 cm².
- [7] Device mounted on 4-layer PCB 70 µm copper strip line, tin-plated and standard footprint.
- [8] Device mounted on 4-layer PCB 70 μm copper strip line, tin-plated, mounting pad for collector 1 cm².

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120 V, 1 A NPN/NPN low VCEsat (BISS) transistor



- (1) 4-layer PCB 70 μm, mounting pad for collector 1 cm²
- (2) FR4 PCB 70 µm, mounting pad for collector 1 cm²
- (3) 4-layer PCB 70 µm, standard footprint
- (4) 4-layer PCB 35 μm, mounting pad for collector 1 cm²
- (5) FR4 PCB 35 μm , mounting pad for collector 1 cm²
- (6) 4-layer PCB 35 µm, standard footprint
- (7) FR4 PCB 70 µm, standard footprint
- (8) FR4 PCB 35 µm, standard footprint

Fig. 1. Per transistor: power derating curves

6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Unit		
Per transisto	Per transistor								
R _{th(j-a)}	thermal resistance		[1]	-	-	338	K/W		
	from junction to ambient		[2]	-	-	219	K/W		
ambient		[3]	-	-	236	K/W			
		[4]	-	-	179	K/W			
			[5]	-	-	278	K/W		
			[6]	-	-	164	K/W		
			[7]	-	-	179	K/W		
			[8]	-	-	86	K/W		
R _{th(j-sp)}	thermal resistance from junction to solder point			-	-	30	K/W		

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Per device	('					
R _{th(j-a)}	thermal resistance in free air	[1]	-	-	245	K/W	
	-	ambient	[2]	-	-	160	K/W
	ambient		[3]	-	-	171	K/W
			[4]	-	-	130	K/W
			[5]	-	-	202	K/W
		[6]	-	-	120	K/W	
			[7]	-	-	130	K/W
			[8]	-	-	63	K/W

- [1] Device mounted on an FR4 PCB, single-sided 35 µm copper strip line, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided 35 μm copper strip line, tin-plated, mounting pad for collector 1 cm².
- [3] Device mounted on 4-layer PCB 35 µm copper strip line, tin-plated and standard footprint.
- [4] Device mounted on 4-layer PCB 35 µm copper strip line, tin-plated, mounting pad for collector 1 cm².
- [5] Device mounted on an FR4 PCB, single-sided 70 µm copper strip line, tin-plated and standard footprint.
- [6] Device mounted on an FR4 PCB, single-sided 70 μm copper strip line, tin-plated, mounting pad for collector 1 cm².
- [7] Device mounted on 4-layer PCB 70 µm copper strip line, tin-plated and standard footprint.
- [8] Device mounted on 4-layer PCB 70 μm copper strip line, tin-plated, mounting pad for collector 1 cm².

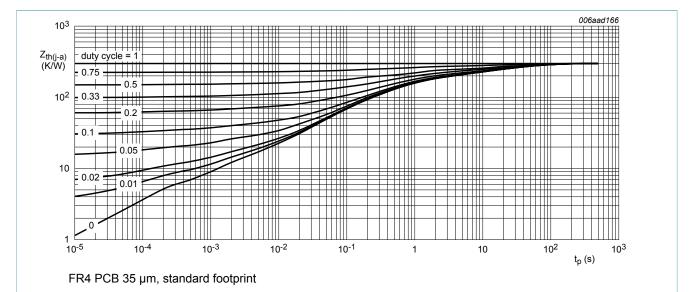


Fig. 2. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

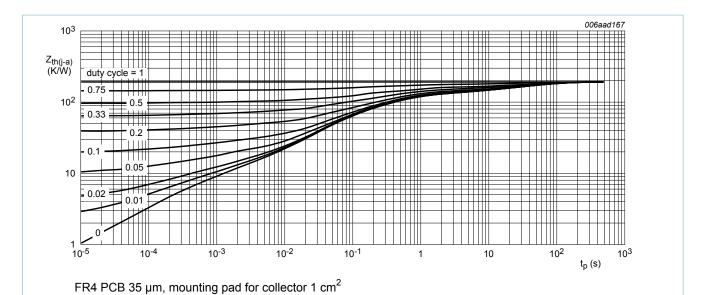


Fig. 3. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

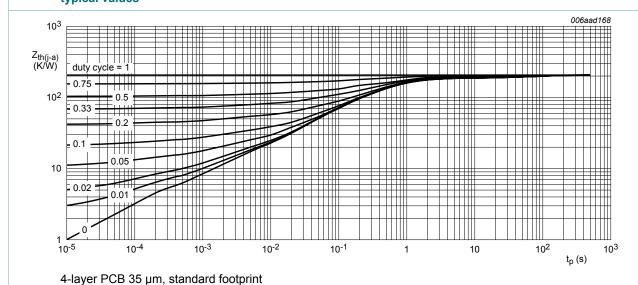


Fig. 4. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

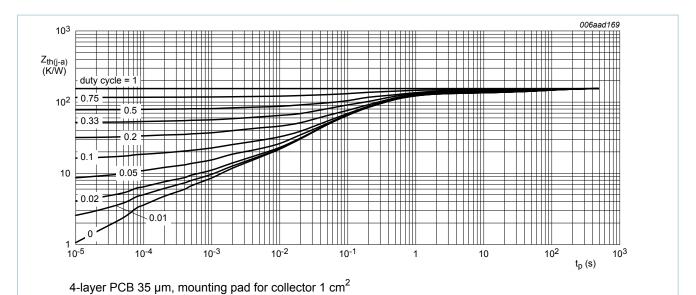
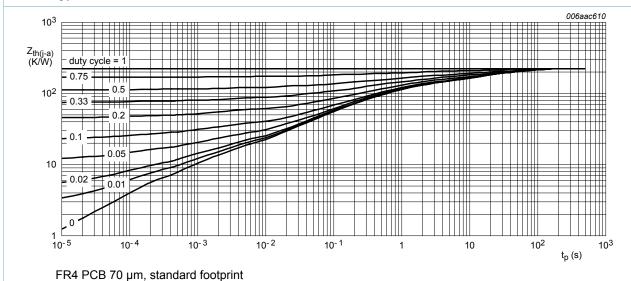


Fig. 5. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 FCB 70 μm, Standard Ιοοιρππί

Fig. 6. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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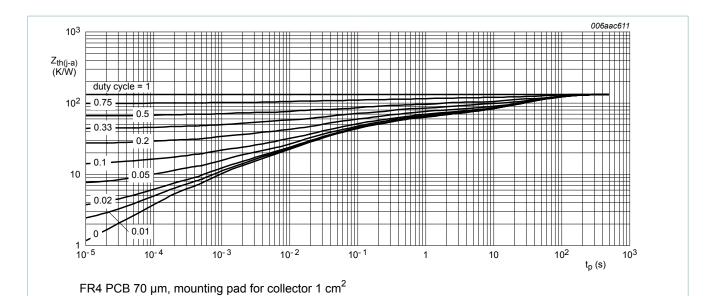


Fig. 7. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

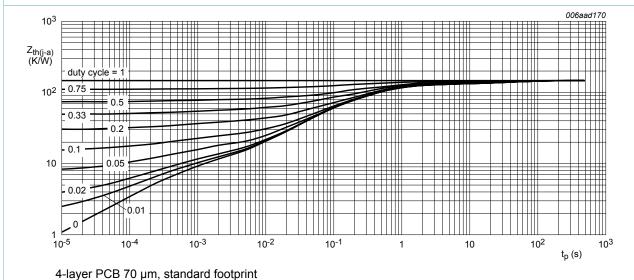


Fig. 8. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

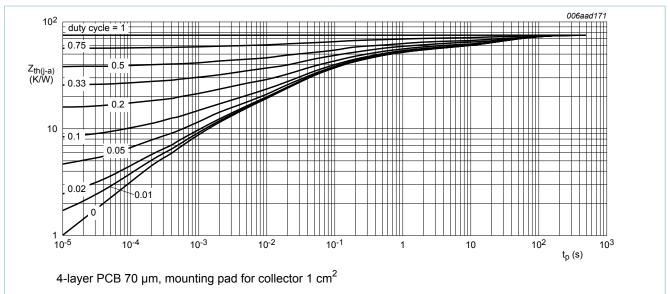


Fig. 9. Per transistor: transient thermal impedance from junction to ambient as a function of pulse duration; typical values

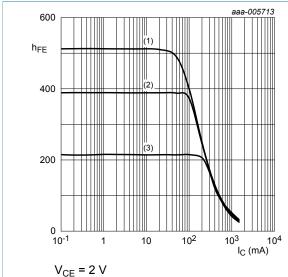
7. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
Per transistor							
I _{CBO}	collector-base cut-off	V _{CB} = 96 V; I _E = 0 A; T _{amb} = 25 °C	-	-	100	nA	
	current	V _{CB} = 96 V; I _E = 0 A; T _j = 150 °C	-	-	50	μA	
I _{EBO}	emitter-base cut-off current	V _{EB} = 5 V; I _C = 0 A; T _{amb} = 25 °C	-	-	100	nA	
h _{FE} DC current gain	DC current gain	V_{CE} = 2 V; I_{C} = 100 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 ; T_{amb}$ = 25 °C	240	375	-		
		V_{CE} = 2 V; I_{C} = 500 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; \ T_{amb}$ = 25 °C	60	100	-		
		V_{CE} = 2 V; I_{C} = 1 A; pulsed; t_{p} ≤ 300 μs; δ ≤ 0.02 ; T_{amb} = 25 °C	30	45	-		
V _{CEsat}	collector-emitter	I _C = 500 mA; I _B = 50 mA; T _{amb} = 25 °C	-	90	120	mV	
	saturation voltage	I_C = 1 A; I_B = 50 mA; pulsed; $t_p \le 300 \ \mu s$; δ ≤ 0.02 ; T_{amb} = 25 °C	-	205	260	mV	
		I_{C} = 1 A; I_{B} = 100 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; \ T_{amb}$ = 25 °C	-	170	220	mV	
R _{CEsat}	collector-emitter saturation resistance	I_C = 500 mA; I_B = 50 mA; pulsed; $t_p \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	-	-	240	mΩ	

120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
22001	base-emitter saturation	I_C = 500 mA; I_B = 50 mA; T_{amb} = 25 °C	-	-	1	V
	voltage	I_C = 1 A; I_B = 50 mA; pulsed; $t_p \le 300$ μs; $\delta \le 0.02$; T_{amb} = 25 °C	-	-	1.1	V
		I_{C} = 1 A; I_{B} = 100 mA; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; \ T_{amb}$ = 25 °C	-	-	1.1	V
V_{BEon}	base-emitter turn-on voltage	V_{CE} = 2 V; I_{C} = 0.5 A; pulsed; $t_{p} \le 300 \ \mu s; \ \delta \le 0.02 \ ; T_{amb}$ = 25 °C	-	-	0.9	V
t _d	delay time	V _{CC} = 10 V; I _C = 500 mA; I _{Bon} = 25 mA;	-	20	-	ns
t _r	rise time	I _{Boff} = -25 mA; T _{amb} = 25 °C	-	440	-	ns
t _{on}	turn-on time		-	460	-	ns
ts	storage time		-	615	-	ns
t _f	fall time		-	390	-	ns
t _{off}	turn-off time		-	1005	-	ns
f _T	transition frequency	V_{CE} = 10 V; I_{C} = 50 mA; f = 100 MHz; T_{amb} = 25 °C	60	120	-	MHz
C _c	collector capacitance	V _{CB} = 10 V; I _E = 0 A; i _e = 0 A; f = 1 MHz; T _{amb} = 25 °C	-	4.5	7	pF

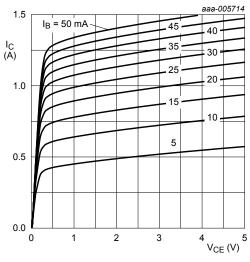


(1) T_{amb} = 100 °C

(2) T_{amb} = 25 °C

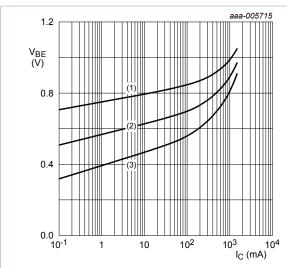
(3) $T_{amb} = -55 \, ^{\circ}C$

Fig. 10. DC current gain as a function of collector current; typical values



 T_{amb} = 25 °C

Fig. 11. Collector current as a function of collectoremitter voltage; typical values



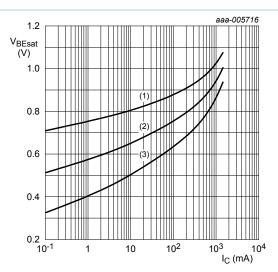
$$V_{CE} = 2 V$$

(1)
$$T_{amb} = -55 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb}$$
 = 100 °C

Fig. 12. Base-emitter voltage as a function of collector current; typical values



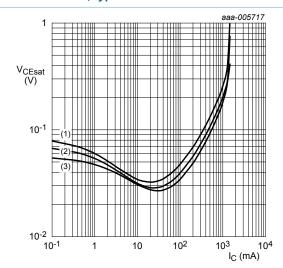
$$I_{\rm C}/I_{\rm B} = 20$$

(1)
$$T_{amb} = -55 \, ^{\circ}C$$

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb} = 100 \, ^{\circ}C$$

Fig. 13. Base-emitter saturation voltage as a function of collector current; typical values



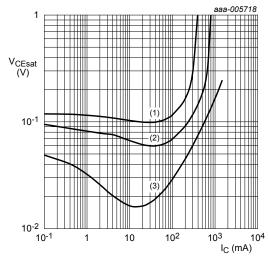
$$I_{\rm C}/I_{\rm B} = 20$$

(1)
$$T_{amb} = 100 \, ^{\circ}C$$

(2)
$$T_{amb}$$
 = 25 °C

$$(3) T_{amb} = -55 °C$$

Fig. 14. Collector-emitter saturation voltage as a function of collector current; typical values



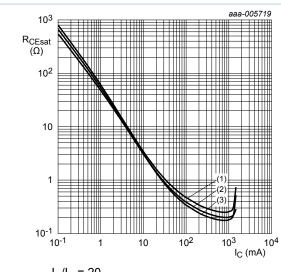
$$T_{amb} = 25 \, ^{\circ}C$$

(1)
$$I_C/I_B = 100$$

(2)
$$I_C/I_B = 50$$

(3)
$$I_C/I_B = 10$$

Fig. 15. Collector-emitter saturation voltage as a function of collector current; typical values



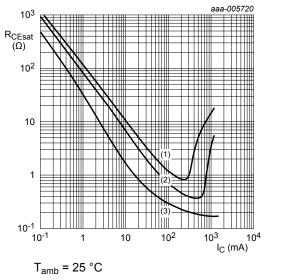
$$I_C/I_B = 20$$

(1)
$$T_{amb}$$
 = 100 °C

(2)
$$T_{amb} = 25 \, ^{\circ}C$$

(3)
$$T_{amb} = -55 \, ^{\circ}C$$

Fig. 16. Collector-emitter saturation resistance as a function of collector current; typical values



(1)
$$I_C/I_B = 100$$

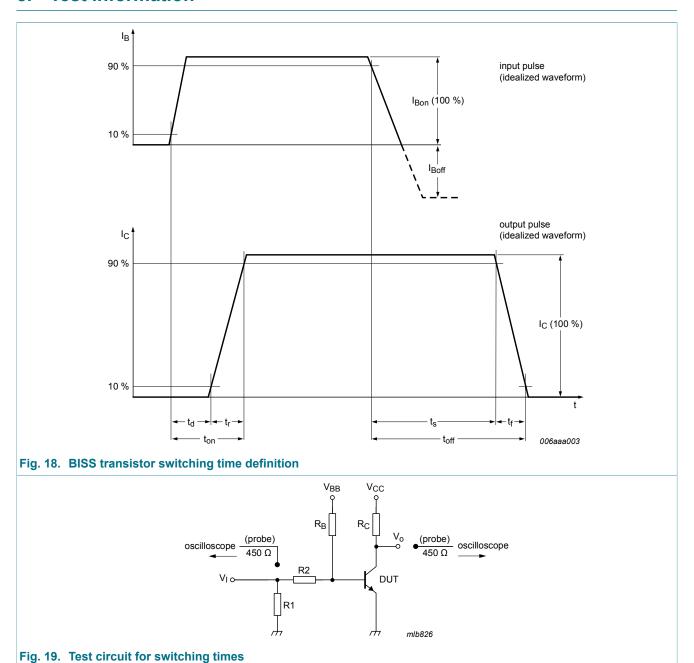
(2)
$$I_C/I_B = 50$$

(3)
$$I_C/I_B = 10$$

Fig. 17. Collector-emitter saturation resistance as a function of collector current; typical values

120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

8. Test information

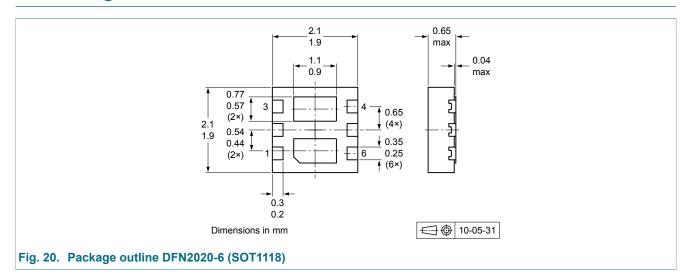


8.1 Quality information

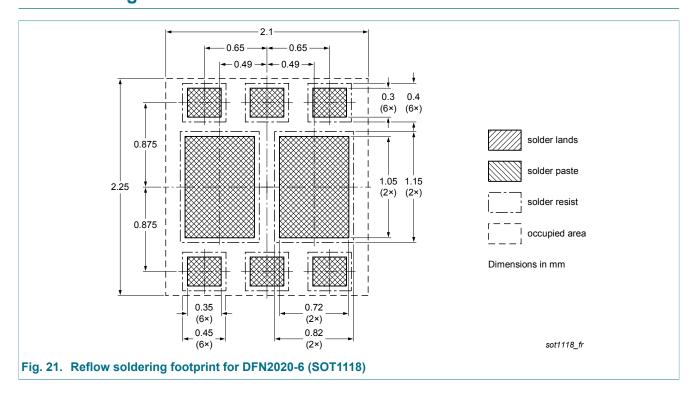
This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

9. Package outline



10. Soldering



11. Revision history

Table 8. Revision history

······································						
Data sheet ID	Release date	Data sheet status	Change notice	Supersedes		
PBSS4112PAN v.N	20121129	Product data sheet	-	-		

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120 V, 1 A NPN/NPN low VCEsat (BISS) transistor

12. Legal information

12.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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